

<b>Notice of References Cited</b>		Application/Control No. 09/783,707	Applicant(s)/Patent Under Reexamination LENZ ET AL.	
		Examiner Patrick J Assouad	Art Unit 2857	Page 1 of 1

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	B	US-2002/0183971 a1	12-2002	Wegerich et al.	702/185
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Chen et al., "SRDE -- Application of Data Similarity to Process Control", 12/1/99.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.